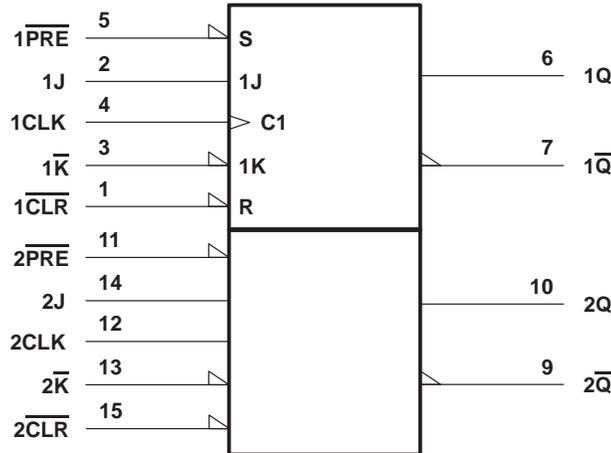


SN54F109, SN74F109

DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH CLEAR AND PRESET

SDFS047A – MARCH 1987 – REVISED OCTOBER 1993

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–1.2 V to 7 V
Input current range	–30 mA to 5 mA
Voltage range applied to any output in the high state	–0.5 V to V_{CC}
Current into any output in the low state	40 mA
Operating free-air temperature range: SN54F109	–55°C to 125°C
SN74F109	0°C to 70°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

	SN54F109			SN74F109			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage			0.8			0.8	V
I_{IK} Input clamp current			–18			–18	mA
I_{OH} High-level output current			–1			–1	mA
I_{OL} Low-level output current			20			20	mA
T_A Operating free-air temperature	–55		125	0		70	°C

SN54F109, SN74F109 DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH CLEAR AND PRESET

SDFS047A – MARCH 1987 – REVISED OCTOBER 1993

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	SN54F109			SN74F109			UNIT
		MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	$V_{CC} = 4.5\text{ V}$, $I_I = -18\text{ mA}$	-1.2			-1.2			V
V_{OH}	$V_{CC} = 4.5\text{ V}$, $I_{OH} = -1\text{ mA}$	2.5	3.4		2.5	3.4		V
	$V_{CC} = 4.75\text{ V}$, $I_{OH} = -1\text{ mA}$	2.7						
V_{OL}	$V_{CC} = 4.5\text{ V}$, $I_{OL} = 20\text{ mA}$	0.3 0.5			0.3 0.5			V
I_I	$V_{CC} = 5.5\text{ V}$, $V_I = 7\text{ V}$	0.1			0.1			mA
I_{IH}	$V_{CC} = 5.5\text{ V}$, $V_I = 2.7\text{ V}$	20			20			μA
I_{IL}	J, \bar{K} , CLK	$V_{CC} = 5.5\text{ V}$, $V_I = 0.5\text{ V}$			-0.6			mA
	\bar{PRE} or \bar{CLR}				-1.8			
I_{OS}^\ddagger	$V_{CC} = 5.5\text{ V}$, $V_O = 0$	-60	-150		-60	-150		mA
I_{CC}	$V_{CC} = 5.5\text{ V}$, See Note 2	11.7	17		11.7	17		mA

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: I_{CC} is measured with J, \bar{K} , CLK, and \bar{PRE} grounded then with J, \bar{K} , CLK, and \bar{CLR} grounded.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

		$V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$		SN54F109		SN74F109		UNIT
		'F74						
		MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency	0	100	0	70	0	90	MHz
t_w	Pulse duration	CLK high, \bar{PRE} or \bar{CLR} low		4	4	4	4	ns
		CLK low		5	5	5	5	
t_{su}	Setup time, data before CLK \uparrow	High		3	3	3	3	ns
		Low		3	3	3	3	
	Setup time, inactive-state before CLK \uparrow §	\bar{PRE} or \bar{CLR} to CLK		2	2	2	2	
t_h	Hold time, data after CLK \uparrow	High		1	1	1	1	ns
		Low		1	1	1	1	

§ Inactive-state setup time is also referred to as recovery time.

switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5\text{ V}$, $C_L = 50\text{ pF}$, $R_L = 500\ \Omega$, $T_A = 25^\circ\text{C}$			$V_{CC} = 4.5\text{ V to }5.5\text{ V}$, $C_L = 50\text{ pF}$, $R_L = 500\ \Omega$, $T_A = \text{MIN to MAX}^\ddagger$				UNIT
			'F109			SN54F109		SN74F109		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{max}			100	150		70		90	MHz	
t_{PLH}	CLK	Q or \bar{Q}	3	4.9	7	3	9	3	8	ns
t_{PHL}			3.6	5.8	8	3.6	10.5	3.6	9.2	
t_{PLH}	\bar{PRE} or \bar{CLR}	Q or \bar{Q}	2.4	4.8	7	2.4	9	2.4	8	ns
t_{PHL}			2.7	6.6	9	2.7	11.5	2.7	10.5	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 3: Load circuits and waveforms are shown in Section 1.



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